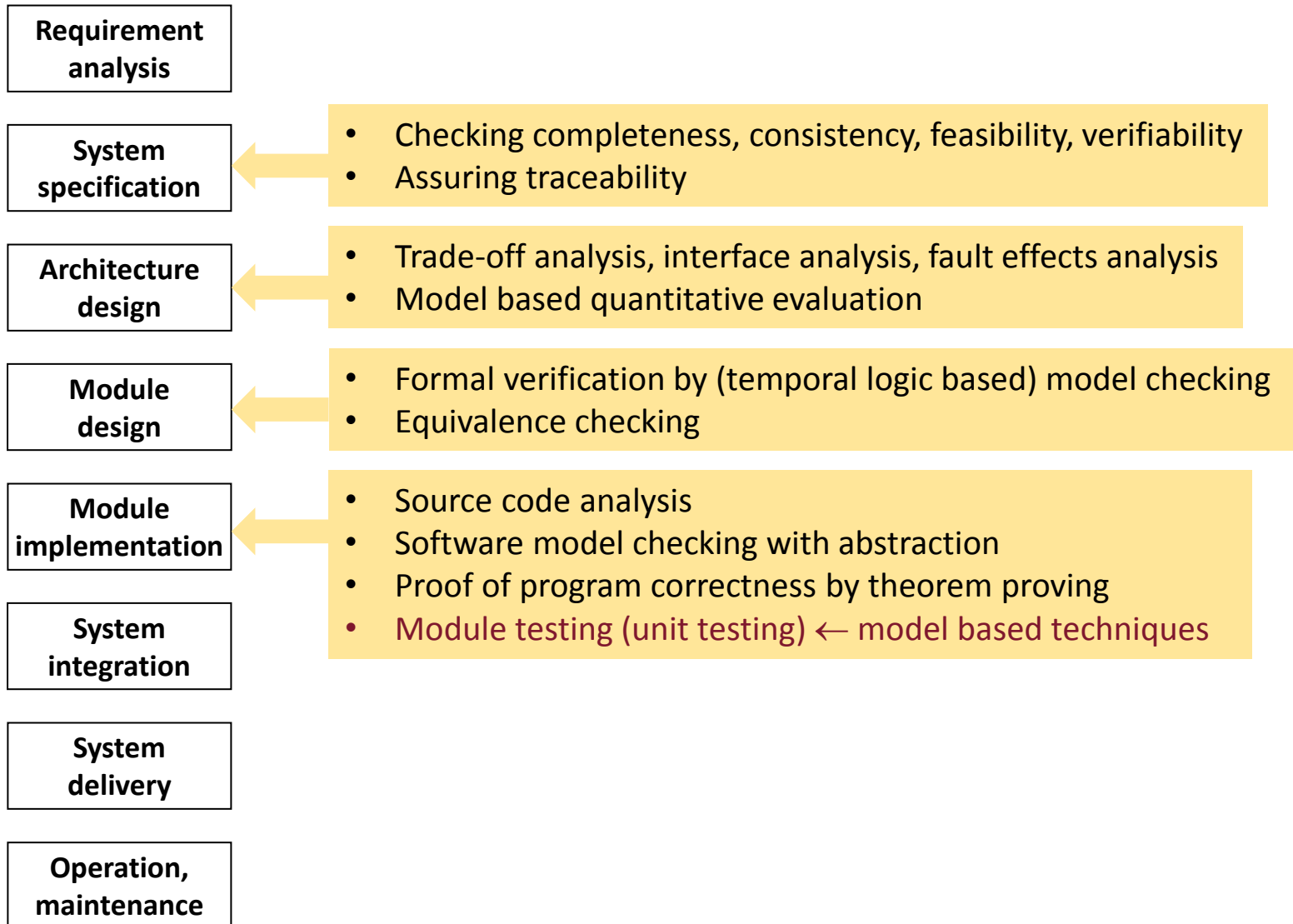


Model based testing

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Typical development steps and V&V tasks



Overview

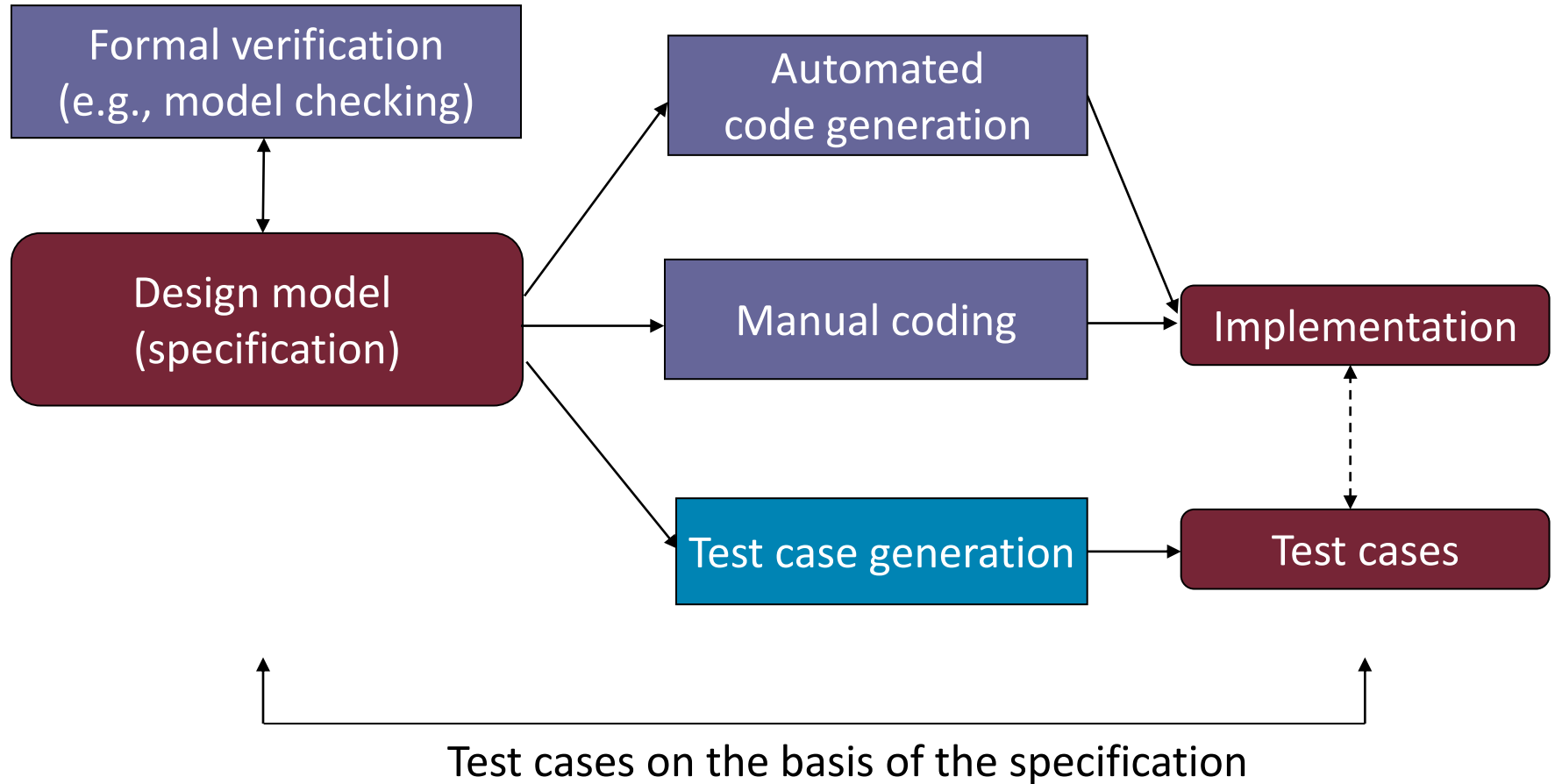
- Introduction
 - The role of models in testing
 - Use cases for model based testing
- Test case generation **for test coverage metrics**
 - Using graph-based (direct) algorithms
 - Using model checkers
 - Using bounded model checkers
- Test case generation **on the basis of mutations**
 - Model mutations
- Conformance and refinement **relations for testing**
 - May and must preorder, IOCO
- + **Tools** for model based test case generation

Introduction

Common practice: UML models in manual testing

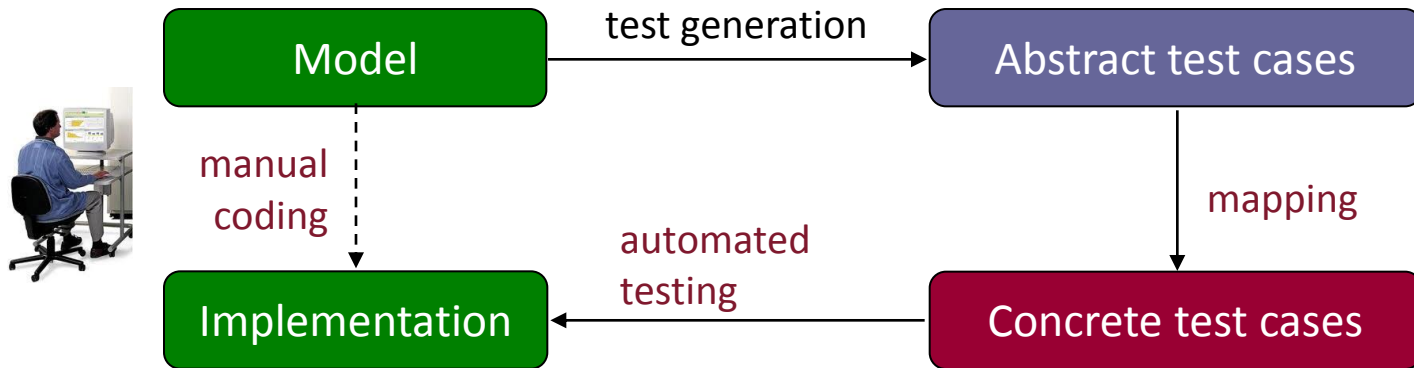
- **Use case diagrams:**
 - Validation (acceptance) testing: Covering use cases
- **Class and object diagrams**
 - Module testing: Identifying sw components, interfaces
- **State machine and activity diagrams:**
 - Module testing: Reference for structure based testing
- **Sequence and collaboration diagrams:**
 - Integration testing: Identifying scenarios
- **Component diagram:**
 - System testing: Identifying physical components
- **Deployment diagram:**
 - System testing: Designing test configuration

Model based test case generation: Typical approach

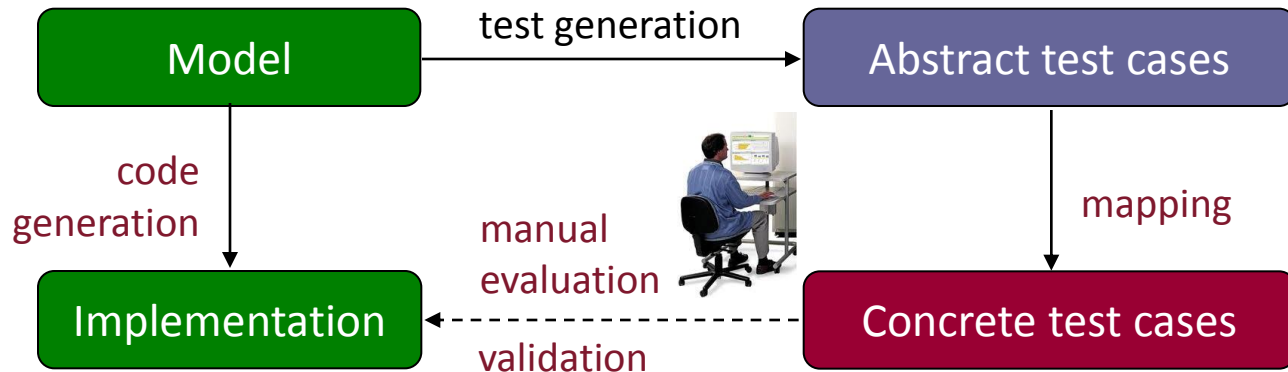


Use cases for model based testing

- In case of manual coding: **Conformance checking**

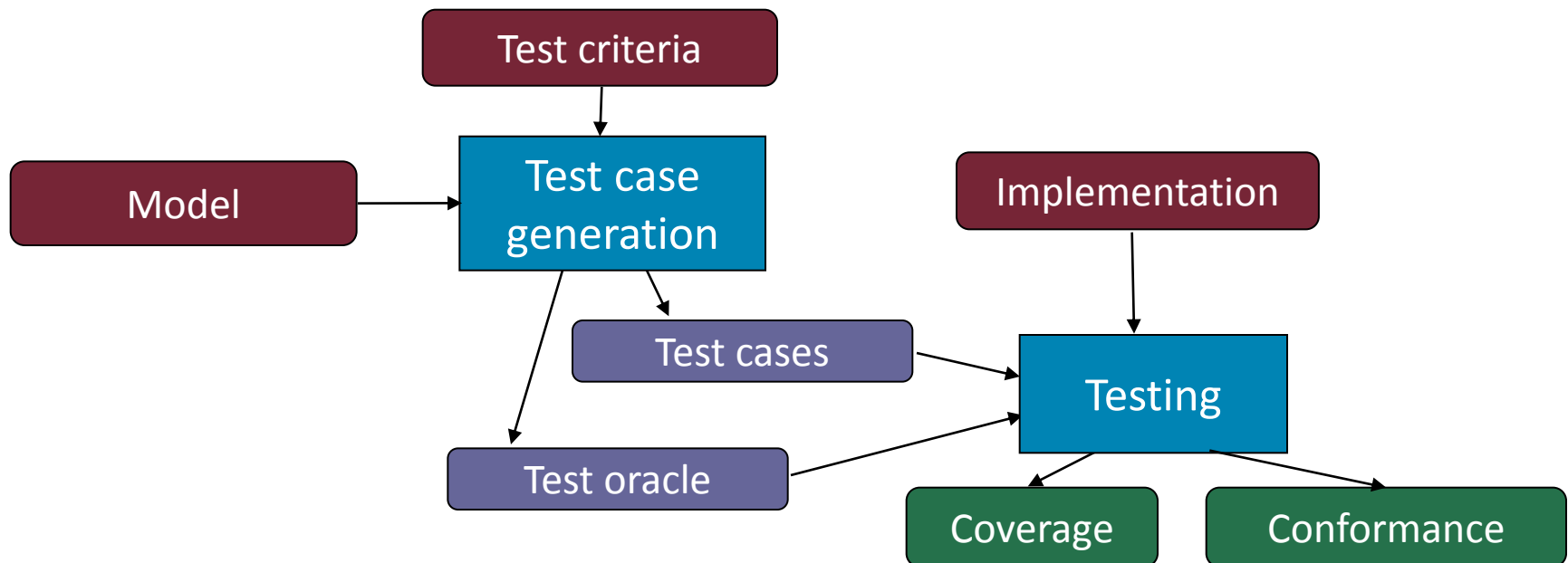


- In case of automated code generation: **Validation**

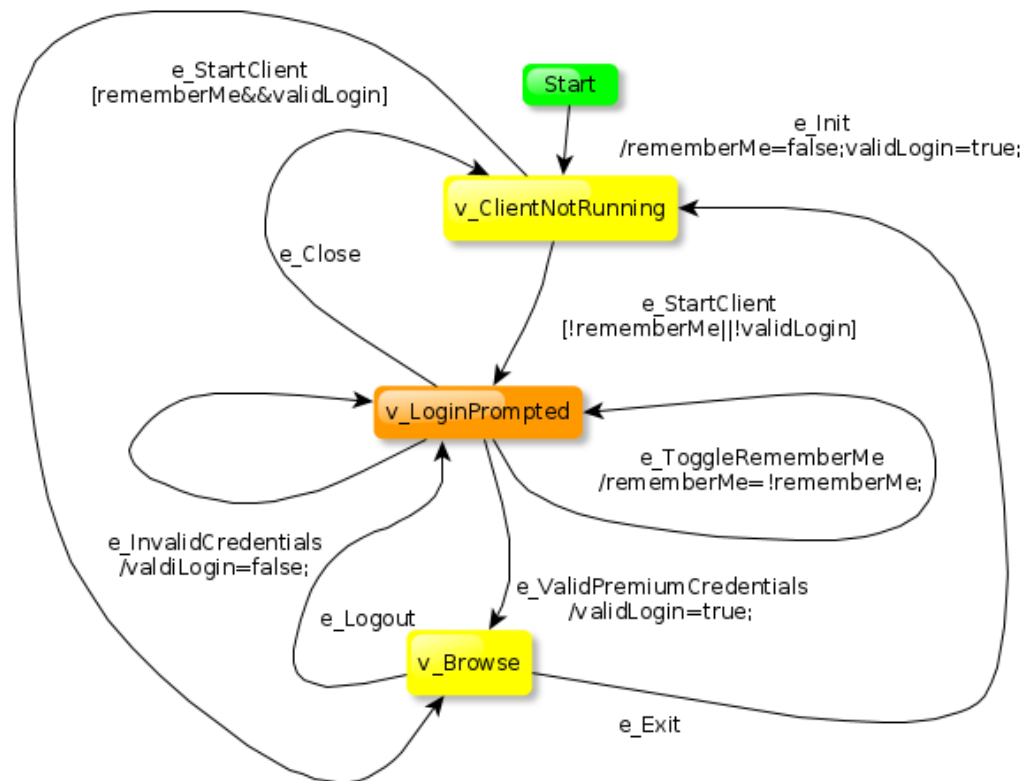


Basic tasks for model based testing (MBT)

- Based on the **model** and the **test criteria**:
 - Test case generation (for coverage or behavior conformance)
 - Test oracle generation (synthesis)
 - Test coverage analysis (for the model)
 - Conformance verdict (between model and implementation)



Example open source tool: GraphWalker



Source: [GraphWalker](#)

- Input: Finite state machine model + simple guards
- Output: Tests for state and transition coverage
+ Generating JUnit test stubs (adapter)
- Traversing the graph: random walk, graph based search, shortest path

Example industrial MBT tool: Conformiq

The screenshot displays the Conformiq Designer IDE interface. It includes several key components:

- Project Explorer (1):** Shows the project structure for 'BLUETOOTH', including files like 'Main.cqa', 'ProtocolException.cqa', 'SDPClient.cqa', 'SDPClient.ami', and 'SystemBlock.cqa'.
- Testing Goals (2):** A table listing various requirements and their coverage status. For example, 'SDP_ErrorResponse' has a goal of 'Must not allow invalid PDU parameter length' with a coverage of 100%.
- Model Browser (4):** Displays a UML diagram of the 'SDP-client' component, showing its internal structure and connections.
- Test Cases (3):** A UML sequence diagram showing interactions between 'appIn', 'clientBTOut', 'clientBTIn', 'appOut', and 'SDP-client'. It includes messages like 'ServiceSearchAttributeIndividual' and 'SDP_ServiceSearchAttributeRequest'.
- State Machine (5):** A state transition diagram for 'SDPClient' with states like 'SDPClient.initial-state-0', 'SDPClient.Process', and 'SDPClient.Process.initial-state-1'.
- Console (6):** Shows the execution output, including messages and field values such as 'ServiceSearchAttributeIndividual' and 'TransactionContinued'.

Conformiq Designer IDE for automatic test case generation

- Input: State machine models + Java action code
- Output: Tests for state, transition, requirement coverage
- Integration with other tools for testing

Source: Conformiq. „Testing Bluetooth Protocol Stacks with Computer-Generated Tests”. Technology brief. 2010

Overview of algorithms for model based test generation

- **Graph-based** algorithms
 - Model represented as a graph + traversal/search in this graph
- Application of **model checkers**
 - Counterexample is a test sequence for specified coverage
 - Symbolic or bounded model checkers
- **Mutation based** test generation algorithms
 - Test goal: Detect model mutations → detect code bugs
- **Planner** based methods
 - The planner constructs an operation sequence for a test goal
- **Evolutionary** algorithms (e.g., genetic algorithms)
 - Modifying an initial test suite generated by random walk
 - Optimization: increase coverage, reduce test length, ...
- **Symbolic execution**
 - Control flow automata model

Graph-based algorithms for test generation

Typical applications of graph-based algorithms

- **Model:** Represents state based, event driven behavior
 - Transitions triggered by input events
 - Actions are given as outputs
- **Basic formalisms:**
 - **Finite state automata** (FSM; Mealy, Moore, ...)
 - Higher level formalisms mapped to automata (UML statecharts, SCADE Safe Statechart, Simulink Stateflow, ...)
- **Typical applications**
 - User interfaces, web based applications
 - Embedded controllers
 - Communication protocols
- **Graph based algorithms**
 - Different algorithms for various testing tasks and test criteria
 - Generating optimal test suite: Typically NP-complete

Graph-based algorithm for transition coverage

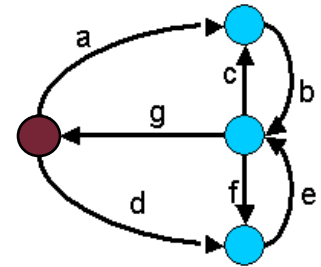
■ Mapping the problem

○ Testing problem: **Coverage of transitions**

- All transitions shall be covered by a test sequence
- The test sequence shall go back to the initial state

○ Graph-based problem: **"New York street sweeper" problem**

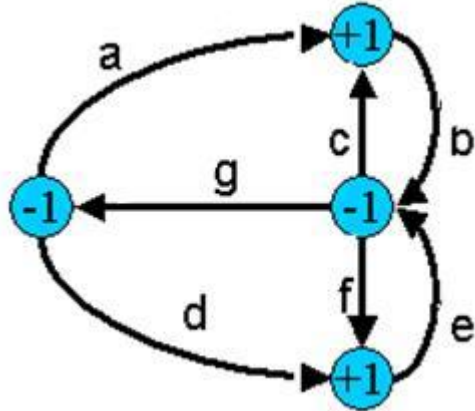
- In a directed graph, find the (shortest) path that covers all transitions and goes back to the initial state
- (The same problem in undirected graphs: "Chinese postman" problem)



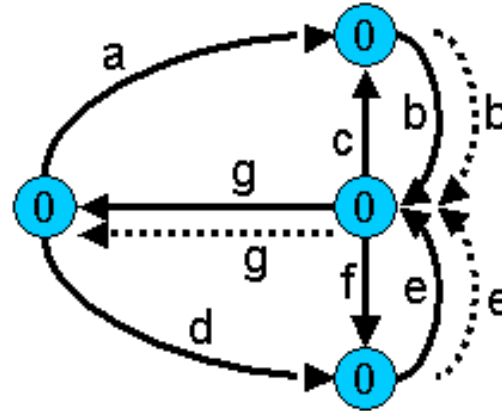
■ Basic idea for the algorithm: Euler-graph → Euler-circuit

- Computing the **polarity** of vertices: nr. of incoming minus outgoing edges
- **Duplicating edges** that lead from a vertex with positive polarity to vertex with negative polarity, until all edges have zero polarity
- **Finding an Euler-circuit** in the resulting graph (linear algorithm)
 - Euler-circuit: All edges are covered, it can always be constructed in such graph
- **The traversal of the Euler-circuit** defines the test sequence

Example: Transition coverage



Original graph with polarities of vertices



Graph with duplicated edges (this way having an Euler-graph)

Sequence for traversal (Euler-circuit):

a b c b f e g d e g

Graph-based algorithm for covering transition pairs

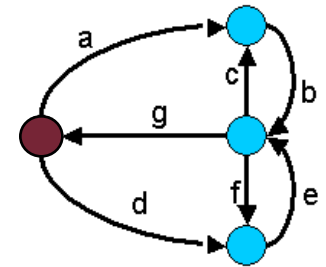
■ Mapping the problem

○ Testing problem: Coverage of transition sequences

- All possible sequences of n subsequent transitions shall be covered by a test sequence
- The test sequence shall go back to the initial state
- Simplest case: Covering all transition pairs

○ Graph-based problem: “Safecracker” sequence

- Find the (shortest) edge sequence that includes all possible sequences of n subsequent edges (simplest case: $n=2$)



■ Basic idea of the algorithm for $n=2$ (de Bruijn algorithm):

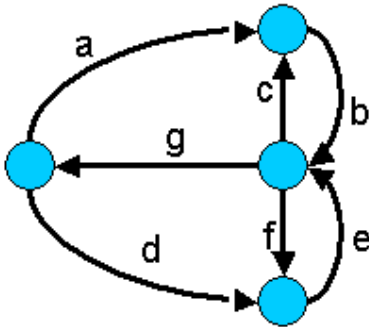
○ Constructing a dual graph

- Edges of the original graph are mapped to vertices
- If there is a pair of subsequent edges in the original graph then an edge is drawn in the dual graph between the vertices that represent these edges

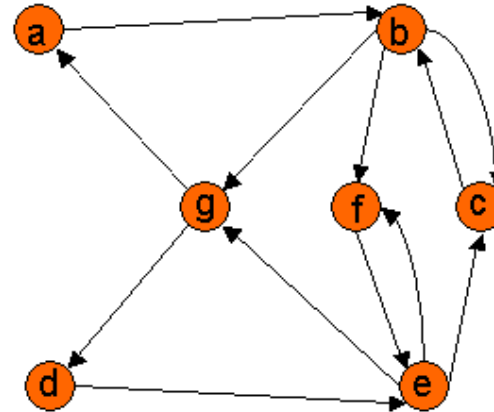
○ Forming an Euler-graph (by duplicating edges) from the dual graph

○ Finding an Euler-circuit that defines the test sequence

Example: Covering transition pairs



Original graph



Dual graph with edges representing edge pairs in the original graph

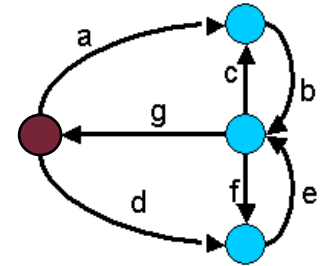
Sequence for traversal that cover all transition pairs:

a b c b f e c b g d e f e g

Graph-based algorithm for concurrent testing

■ Mapping the problem

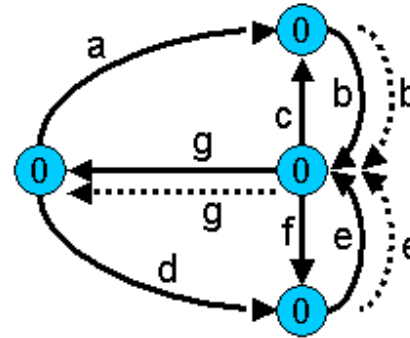
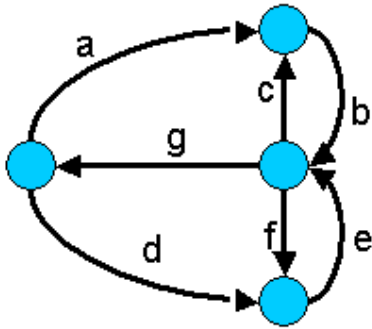
- Testing problem: **Covering all transitions by concurrent testers**
 - Goal is complete transition coverage
 - There are several testers that share (preferably equally) the testing task to finish it in the shortest time
 - All testers start in the initial state
 - Condition: The tested system shall be resetable to the initial state
- Graph-based problems: **"Street sweepers brigade" problem**



■ Solution with heuristics (not an optimal solution)

- Giving an upper limit **k** of the length of the test sequence for each tester
- Generating an edge sequence in the Euler-graph that contains the highest number of edges that were not covered yet, and consists of at most **k** edges
- Generating additional test sequences until uncovered edge exists
- Trying to lower the limit **k** until the number of testers can be increased

Example for concurrent transition coverage



Original test sequence (Euler-circuit, for 1 tester):

a b c b f e g d e g

A potential set of concurrent test sequences (k=7):

○ Tester 1: a b c b f e g

○ Tester 2: d e g

■ A better set of concurrent test sequences (k=5):

○ Tester 1: a b c b g

○ Tester 2: d e f e g

Test generation by model checking

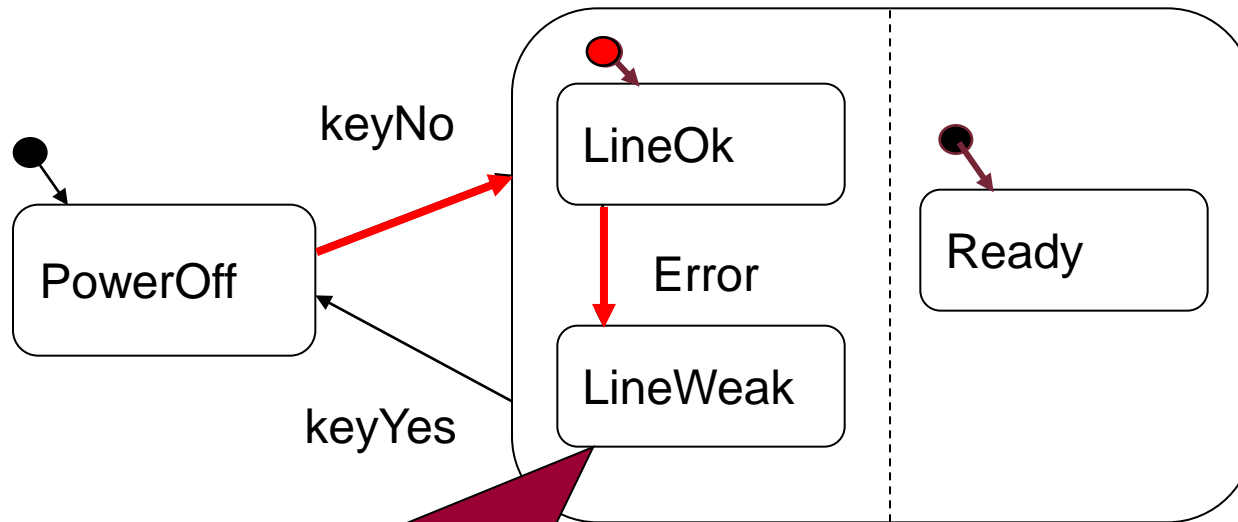
Basic idea

- Typical test coverage criteria (for the model):
 - Control flow based:
 - State coverage, transition coverage
 - Incoming-outgoing transition pairs coverage (for all states)
 - Data flow based:
 - Variable definition and usage coverage (for all variables)
- Required for test generation:
 - Traversal of the state space ← Model checker can perform it
- Basic idea:
 - Let the model checker traverse the state space
 - Let control the model checker in such a way that the counter-examples generated by the model checker form test sequences
 - Proper requirements (temporal logic properties to be checked) are needed – depending on the coverage criteria

Basic idea: Using a model checker for test generation

1. Test sequence to be generated:
Coverage of the state LineWeak

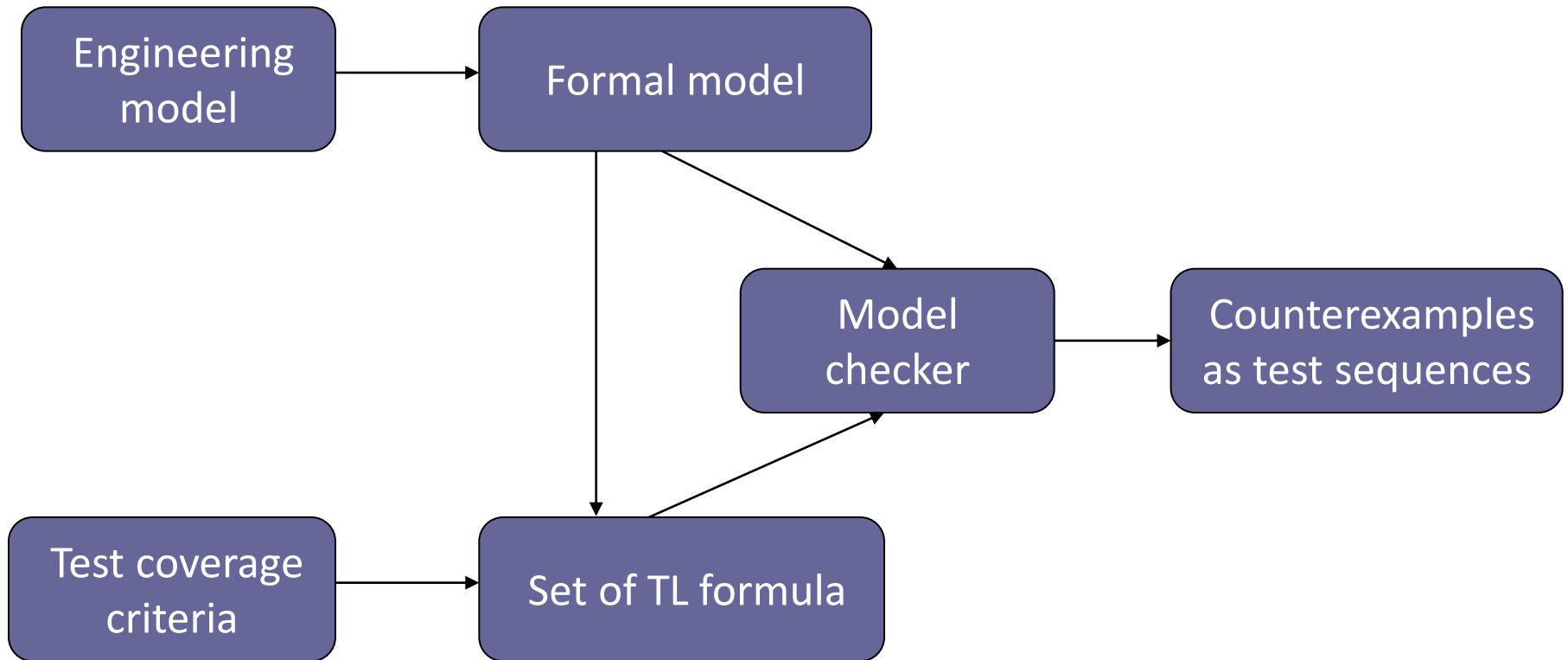
3. The counterexample generated by the model checker demonstrates that the given state can be reached



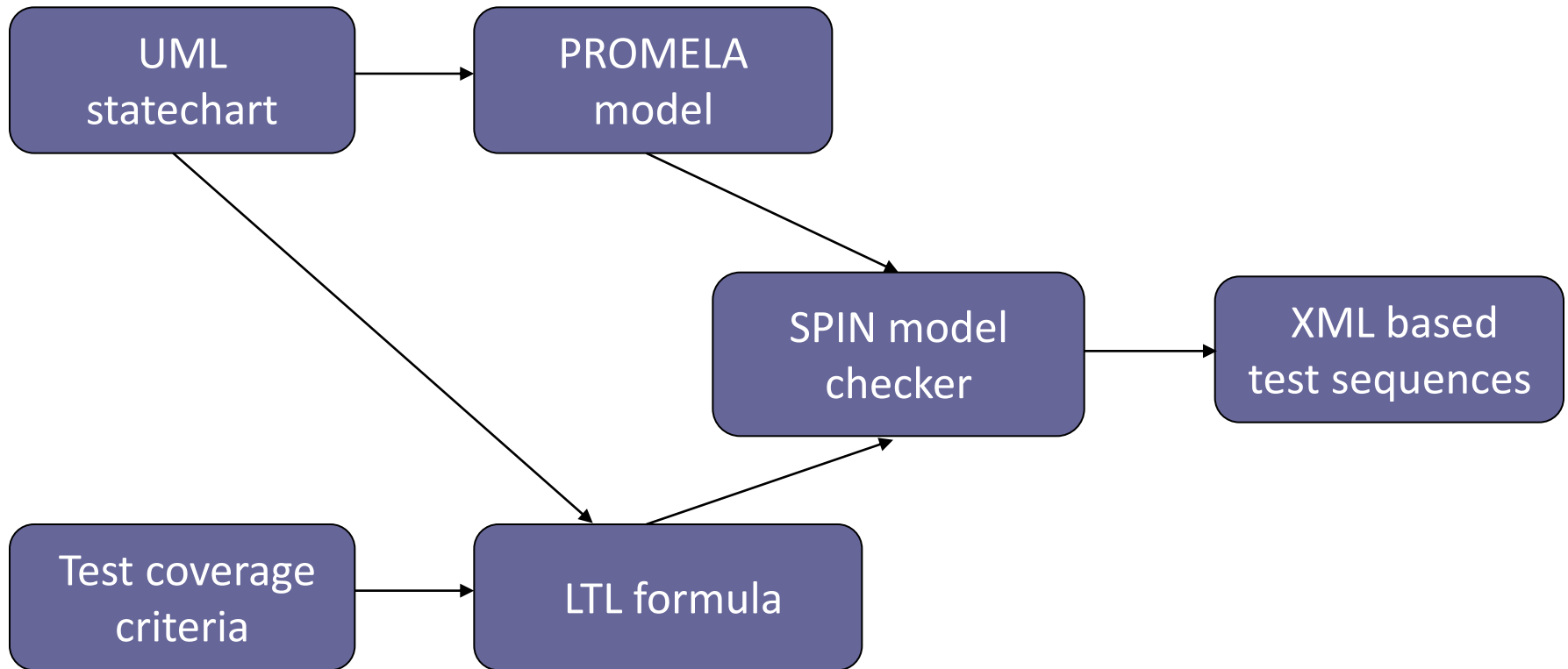
2. Specifying property for the model checker: The state LineWeak cannot be reached:
 $\neg \text{EF LineWeak}$

4. The counterexample is a test sequence covering the state LineWeak

Framework for automated test generation



A possible implementation of the framework



Representing test coverage criteria by TL formula

- Labels in the model for variable v (predicates):

- $\text{def}(v)$
- $\text{c-use}(v)$
- $\text{p-use}(v)$
- $\text{implicit-use}(v)$

Using the variable in **condition** for an **implicit transition**

Implicit transition: The state does not change if the condition of the implicit transition holds

- Characteristic functions (with state variables):

- s : being in state s
- t : executing a given transition t (reaching the target state from the source state)

- State sets (\rightarrow represented by characteristic functions):

- $d(v)$: all $\text{def}(v)$
- $u(v)$: all $\text{c-use}(v)$ or $\text{p-use}(v)$
- $\text{im-u}(v)$: all $\text{implicit-use}(v)$
- start : state for starting new test (e.g., initial state)

Formula for control flow based coverage criteria

- State coverage:

$$\{\neg EF s \mid s \text{ basic state}\}$$

Set of formula is defined

If a predefined start state shall also be reached for the subsequent test:

$$\{\neg EF (s \wedge EF \text{ start}) \mid s \text{ basic state}\}$$

(EF start is omitted from the next formula)

- Weak transition coverage:

$$\{\neg EF t \mid t \text{ transition}\}$$

Strong coverage: Implicit transitions (not leaving the given state) are also tested

- Strong transition coverage:

$$\{\neg EF t \mid t \text{ transition}\} \cup \{\neg EF it \mid it \text{ implicit transition}\}$$

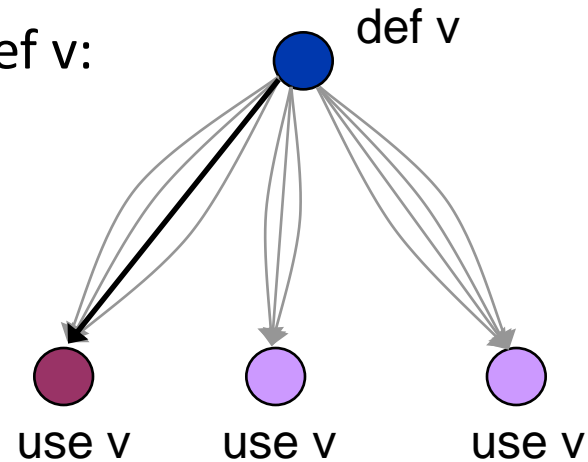
Recap: Data flow based test coverage criteria

■ All-defs:

For all v , from all def v :

at least one
def-clear path:

to at least
one use v :

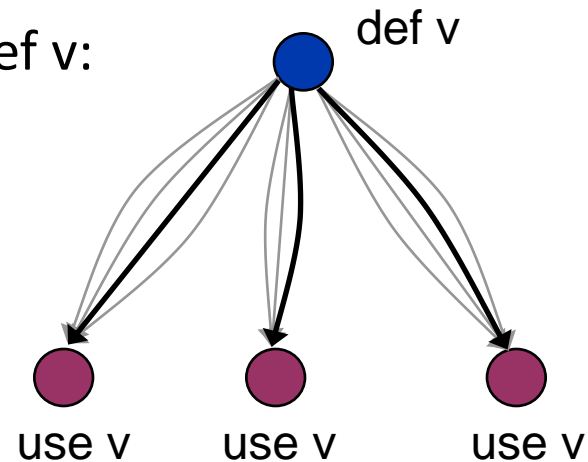


■ All-uses:

For all v , from all def v :

at least one
def-clear path:

to all use v :



Formula for data flow based test coverage criteria

- Weak all-defs coverage:

One def-clear path traversed from all $\text{def}(v)$ to one $\text{use}(v)$

$$\{\neg EF (t \wedge EX E(\neg d(v) \cup u(v))) \mid v \text{ variable, } t \in d(v)\}$$

- Weak all-uses coverage:

One def-clear path traversed from all $\text{def}(v)$ to all $\text{use}(v)$

$$\{\neg EF (t \wedge EX E(\neg d(v) \cup t')) \mid v \text{ variable, } t \in d(v), t' \in u(v)\}$$

- Strong all-defs coverage:

Implicit variable usage: in transitions not leaving the given state

$$\{\neg EF (t \wedge EX E(\neg d(v) \cup (u(v) \vee \text{im-}u(v)))) \mid v \text{ variable, } t \in d(v)\}$$

- Strong all-uses coverage:

$$\{\neg EF (t \wedge EX E(\neg d(v) \cup t')) \mid v \text{ variable, } t \in d(v), t' \in u(v) \cup \text{im-}u(v)\}$$

Features of model checker based test generation

- Capabilities of model checkers:
 - Generating (typically) a single counterexample
 - Test sequences are hard to generate for coverage criteria that require **all paths** (this way all counterexamples)
 - E.g., **all-du-paths** criterion
(**all** def-clear paths for a given def-use pair shall be tested)
- Abstract test sequences are generated
 - Defining the sequence of inputs
 - Expected outputs shall be determined (e.g., by simulation in the model)
 - Mapping is needed to **concrete test sequences**: concrete steps (calls) in a concrete test execution environment

Optimization of test sequences

- Task of model checking:
 - Efficient traversal of the state space: Fast, with low memory needs
- Required for test generation:

Finding fast a counterexample that is **as short as possible**

→ **Specific settings** are needed in the model checker

 - Generating the shortest test sequences: NP-complete problem
- Possible settings (e.g., in case of model checker SPIN):
 - **Breadth first search** (BFS) in the state space
 - Depth first search, but with **limited depth** (limited DFS)
 - Finding shorter test sequences **in an iterative way**
 - **Approximate** model checking (hash function for storing checked states)
 - Some states (also covered by the hash function) will not be traversed
 - If a counterexample is found then it is a real test sequence for coverage

Example: Results for generating test sequences

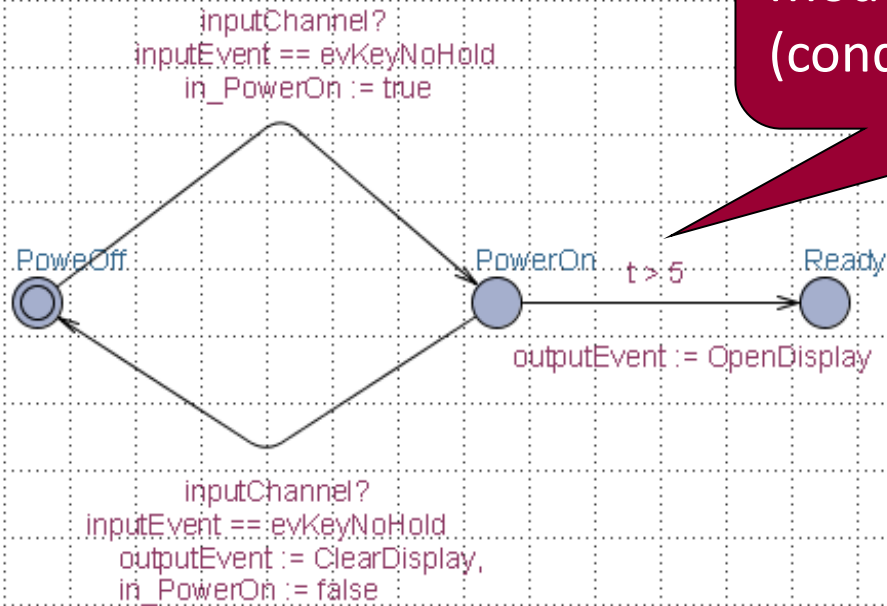
Options (compile time or run-time)	Time required for test generation	Length of all test sequences	Longest test sequence generated
-l	22m 32.46s	17	3
-dBFS	11m 48.83s	17	3
-i -m1000	4m 47.23s	17	3
-l	2m 48.78s	25	6
default	2m 04.86s	385	94
-l -m1000	1m 46.64s	22	4
-m1000	1m 25.48s	97	16
-m200 -w24	46.7s	17	3

Settings:

- -i iterative, -l approx. iterative
- -dBFS breadth first search
- -m limit for depth first search
- -w hash table size

State machine model of the behavior of a mobile phone (10 states, 11 transitions)

Extension of MBT to testing time-dependent behavior



Clock variables:
Modelling time dependency
(conditions, state invariants)

- Timed automata models
- Specific model checker: UPPAAL

Generated counterexamples with timing

State:

```
( input.sending mobile.PowerOn mobile1.LineOK mobile2.CallWait )  
t=0 inputEvent=28 outputEvent=14 in_PowerOn=1 #depth=5
```

Delay: 6

Delays are included between the inputs of the test sequence

State:

```
( input.sending mobile.PowerOn mobile1.LineOK mobile2.CallWait )  
t=6 inputEvent=28 outputEvent=14 in_PowerOn=1 #depth=5
```

Transitions:

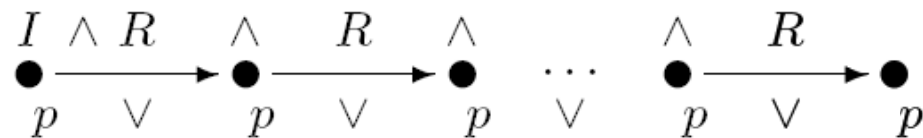
```
input.sending->input.sendInput { 1, inputChannel!, 1 }
```

```
mobile2.CallWait->mobile2.VoiceMail { inputEvent == evKeyYes && t >  
5 && in_PowerOn, inputChannel?, 1 }
```

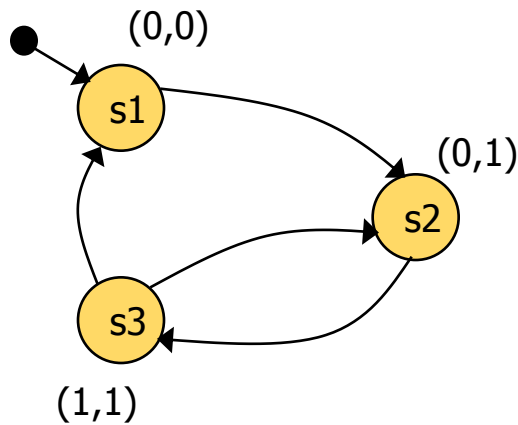
Test generation by bounded model checking

Recap: Bounded model checking

- Using SAT solvers for checking reachability of specific states
 - Given a Boolean formula (Boolean function), SAT solver generates a variable assignment (substitution) that makes the formula true
- Mapping the verification problem to Boolean function:
 - Characteristic function for initial states: $I(s)$
 - Characteristic function for specified “bad” states: $p(s)$
 - Characteristic function of the state transition relation: $C_R(s, s')$
 - “Stepping forward” along the state transitions: $C_R(s^i, s^{i+1})$
- The characterization of a **counterexample** (with conjunction):
 - Starting from the initial state: $I(s)$
 - „Stepping” along the transition relation: $C_R(s, s')$
 - Specifying that $p(s^i)$ holds somewhere along the path



Recap: Encoding a model

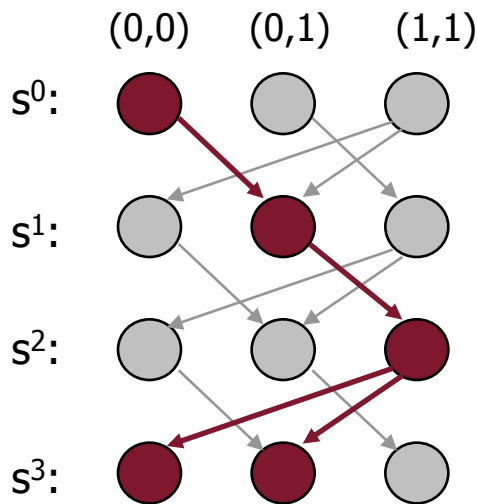


Initial state:

$$I(x,y) = (\neg x \wedge \neg y)$$

Transition relation:

$$\begin{aligned}
 C_R(x,y, x',y') = & (\neg x \wedge \neg y \wedge \neg x' \wedge y') \vee \\
 & \vee (\neg x \wedge y \wedge x' \wedge y') \vee \\
 & \vee (x \wedge y \wedge \neg x' \wedge y') \vee \\
 & \vee (x \wedge y \wedge \neg x' \wedge \neg y')
 \end{aligned}$$



Paths with 3 steps from the initial state:

$$\begin{aligned}
 I(s^0) \wedge \text{path}(s^0, s^1, s^2, s^3) = \\
 = I(x^0, y^0) \wedge \\
 C_R(x^0, y^0, x^1, y^1) \wedge \\
 C_R(x^1, y^1, x^2, y^2) \wedge \\
 C_R(x^2, y^2, x^3, y^3)
 \end{aligned}$$

SAT based test generation for coverage criteria

- Constructing the Boolean function:
 - Encoding paths with k steps from the initial state
 - Specifying test criterion: In general, a TG formula
 - Reaching (covering) a state
 - Executing (covering) a transition
 - Traversing (covering) a part of the model, ...

$$I(s^0) \wedge \bigwedge_{i=0}^{k-1} C_R(s^i, s^{i+1}) \wedge TG$$

The diagram shows the formula $I(s^0) \wedge \bigwedge_{i=0}^{k-1} C_R(s^i, s^{i+1}) \wedge TG$ on a light green background. Below the formula, two arrows point downwards. The left arrow points to the text "Model paths of k length". The right arrow points to the text "Test goal".

- If this formula can be satisfied, then the substitution gives a test
 - This test is according to TG and limited to k steps
 - If there is no substitution then there is no test for TG in k steps

Features of BMC based test generation

- Limitations for test generation
 - Test of max. k steps can be generated
 - The length of paths can be increased iteratively
 - If a test sequence is found then it can be used
 - If there is no test found then a longer test sequence may exist
- Mapping the test generation problem to SAT problem can be made automatically
- The specification of test goals can be simplified
 - For C programs: FQL language for test goals (FSHELL tool)
`in /code.c/ cover @line(6),@call(f1) passing @file(code.c) \ @call(f2)`
 - Specifying pre- and postconditions: Is there a test when the postcondition is not satisfied (although the precondition holds)?

Test generation based on mutations

Using fault sets for test generation

- Experience in software testing:
 - **Coupling effect**: Test cases that are efficient to find simple faults are also efficient for finding more complex faults
 - **Competent programmer hypothesis**: The programs are typically good, and the majority of faults are often occurring typical faults
- Basic idea:
 - Generating “mutant” models that contain typical simple faults, and generate tests for detecting these faults
 - These tests are expected to be more efficient in detecting more complex faults than random tests
- Typical “mutations”:
 - Changing arithmetic operations in conditions
 - Changing the ordering of actions, messages
 - Omission of actions, messages, function calls
 - ...

Equivalence relation for BMC based test generation

- Inputs and outputs are distinguished in the model
 - $\text{in}(s)$ – inputs (events) in state s
 - $\text{out}(s)$ – observable outputs (actions) in state s
 - δ action: lack of observable output
- Definition of the **k-equivalence** for the behaviour of two models:

For the first k steps, providing identical input sequences, the outputs of the two models are the same

- Notation:

Original model M :

$$I(s^0)$$

$$C_R(s^i, s^{i+1})$$

Mutated model M' :

$$I'(s'^0)$$

$$C_R'(s'^i, s'^{i+1})$$

Paths of length k from the initial state:

$$I(s^0) \wedge \bigwedge_{i=0}^{k-1} C_R(s^i, s^{i+1})$$

Mutation based test generation using k-equivalence

- Construction of a SAT formula for detecting a mutation:
 - Providing the same input sequence for the two models
 - Traversing paths of length k in the original model
 - Traversing paths of length k in the mutant model
 - At least one output shall be different in the two models

$$\bigwedge_{i=0}^k (\text{in}(s^i) = \text{in}(s'^i)) \wedge I(s^0) \wedge \bigwedge_{i=0}^{k-1} C_R(s^i, s^{i+1}) \wedge I'(s'^0) \wedge \bigwedge_{i=0}^{k-1} C'_R(s'^i, s'^{i+1}) \wedge \bigvee_{i=0}^k (\text{out}(s^i) \neq \text{out}(s'^i))$$

The diagram illustrates the components of the SAT formula. It is divided into four groups by brackets below the formula:

- The same inputs:** $\bigwedge_{i=0}^k (\text{in}(s^i) = \text{in}(s'^i))$
- Original model:** $I(s^0) \wedge \bigwedge_{i=0}^{k-1} C_R(s^i, s^{i+1})$
- Mutant model:** $I'(s'^0) \wedge \bigwedge_{i=0}^{k-1} C'_R(s'^i, s'^{i+1})$
- At least one output is different:** $\bigvee_{i=0}^k (\text{out}(s^i) \neq \text{out}(s'^i))$

- If this formula can be satisfied then the substitution defines a test
 - The test detects the mutation: An output is different if the mutation is included in the model
 - If there is no substitution then there is no test for k steps

More general problem: Conformance in testing

- Test generation for mutations:
 - Construction of test input sequences that result in **different behavior** in the original (fault-free) and in the mutated model
 - Expected output sequence of the mutation test: Belongs to the mutation
 - These are so-called **negative tests** (failed test: no mutation)
- How to define the “difference” between two behaviors:
What are the faults/mutations that are allowed?
 - Additional behavior besides the specified behavior?
 - Omission of some output?
- Typical solutions
 - Safety critical systems: **Equivalent behavior**, strictly according to the specification (complete specification and implementation are assumed)
 - “Common” systems: **Conformant behavior**, the specification provides the frame (limits) for acceptable behavior (incomplete specification and incomplete implementation are allowed)